

900V GaN FET in TO-220 (source tab)

Description

The TP90H180PS 900V, $170m\Omega$ Gallium Nitride (GaN) FET is a normally-off device. It combines state-of-the-art high voltage GaN HEMT and low voltage silicon MOSFET technologies—offering superior reliability and performance.

Transphorm GaN offers improved efficiency over silicon, through lower gate charge, lower crossover loss, and smaller reverse recovery charge.

Related Literature

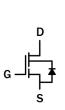
- ANOOOO: Recommended External Circuitry for GaN FETs
- ANOOO3: Printed Circuit Board Layout and Probing
- ANOO10: Paralleling GaN FETs

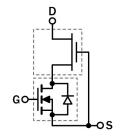
Ordering Information

Part Number	Package	Package Configuration
TP90H180PS	3 lead TO-220	Source

TP90H180PS T0-220 (top view)







Cascode Schematic Symbol

Cascode Device Structure

Features

- JEDEC qualified GaN technology
- Dynamic R_{DS(on)eff} production tested
- · Robust design, defined by
 - Intrinsic lifetime tests
 - Wide gate safety margin
 - Transient over-voltage capability
- Very low Q_{RR}
- Reduced crossover loss
- · RoHS compliant and Halogen-free packaging

Benefits

- Enables AC-DC bridgeless totem-pole PFC designs
 - Increased power density
 - Reduced system size and weight
 - Overall lower system cost
- Achieves increased efficiency in both hard- and softswitched circuits
- · Easy to drive with commonly-used gate drivers
- · GSD pin layout improves high speed design

Applications

- Datacom
- Broad industrial
- PV inverter
- Servo motor

Key Specifications		
V _{DSS} (V)	900	
V _{(TR)DSS} (V)	1000	
$R_{DS(on)eff}(m\Omega)\;max^*$	205	
Q _{RR} (nC) typ	49	
Q _G (nC) typ	10	

^{*} Dynamic on-resistance; see Figures 19 and 20

Absolute Maximum Ratings (T_c=25 °C unless otherwise stated.)

Symbol	Parameter		Limit Value	Unit
V _{DSS}	Drain to source voltage (T _J = -5	55°C to 150°C)	900	
$V_{(TR)DSS}$	Transient drain to source volta	ige ^a	1000	V
V _{GSS}	Gate to source voltage		±18	
P _D	Maximum power dissipation @	T _C =25°C	78	W
1	Continuous drain current @T _C =25°C b		15	А
l _D	Continuous drain current @T _C =100°C b		10	А
I _{DM}	Pulsed drain current (pulse width: 10µs)		58	А
(di/dt) _{RDMC}	Reverse diode di/dt, repetitive	Reverse diode di/dt, repetitive °		A/µs
(di/dt) _{RDMT}	Reverse diode di/dt, transient	Reverse diode di/dt, transient d		A/µs
Tc	Operating temperature	Case	-55 to +150	°C
TJ	Operating temperature	Junction	-55 to +150	°C
Ts	Storage temperature		-55 to +150	°C
T _{SOLD}	Soldering peak temperature ^e		260	°C

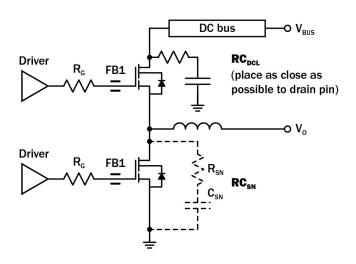
Notes:

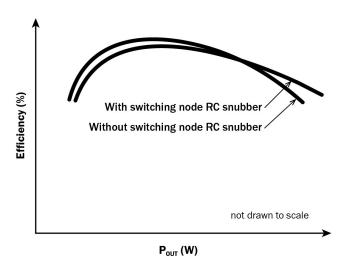
- a. In off-state, spike duty cycle D<0.01, spike duration <1µs
- b. For increased stability at high current operation, see Circuit Implementation on page 3
- c. Continuous switching operation
- d. ≤300 pulses per second for a total duration ≤20 minutes
- e. For 10 sec., 1.6mm from the case

Thermal Resistance

Symbol	Parameter	Typical	Unit
R _{OJC}	Junction-to-case	1.6	°C/W
Roja	Junction-to-ambient	62	°C/W

Circuit Implementation





Simplified Half-bridge Schematic

Efficiency vs Output Power

Recommended gate drive: (0V, 8-10V) with $R_{G(tot)} = 25\Omega$, where $R_{G(tot)} = R_G + R_{DRIVER}$

Gate Ferrite Bead (FB1)	Required DC Link RC Snubber (RC _{DCL}) ^a	Recommended Switching Node RC Snubber (RC _{SN}) ^{b, c}
MMZ1608Q121BTA00	10nF + 8Ω	22pF + 15Ω

Notes:

- a. RC_{DCL} should be placed as close as possible to the drain pin
- b. A switching node RC snubber (C, R) is recommended for high switching currents (>70% of IRDMC1 or IRDMC2; see page 5 for IRDMC1 and IRDMC2)
- c. I_{RDM} values can be increased by increasing R_{G} and C_{SN}

Electrical Parameters (T_J=25 °C unless otherwise stated)

Symbol	Parameter		Тур	Max	Unit	Test Conditions	
Forward	Forward Device Characteristics						
$V_{(BL)DSS}$	Drain-source voltage	900	_	_	V	V _{GS} =0V	
$V_{\text{GS(th)}}$	Gate threshold voltage	1.6	2.1	2.6	V	V _{DS} =V _{GS} , I _D =0.5mA	
Б	Duning and understanding a	_	170	205		V _{GS} =10V, I _D =10A	
R _{DS(on)eff}	Drain-source on-resistance ^a	_	350	_	mΩ	V _{GS} =10V, I _D =10A, T _J =150°C	
	Duein to accuracy lands of a command	_	2.5	30		V _{DS} =900V, V _{GS} =0V	
I _{DSS}	Drain-to-source leakage current	_	12	_	μA	V _{DS} =900V, V _{GS} =0V, T _J =150°C	
	Coto to course forward looks on surrout	_	_	100	1	V _{GS} =18V	
I _{GSS}	Gate-to-source forward leakage current	_	_	-100	· nA	V _{GS} =-18V	
C _{ISS}	Input capacitance	_	780	_			
Coss	Output capacitance	_	41	_	pF	V _{GS} =0V, V _{DS} =600V, <i>f</i> =1MHz	
C _{RSS}	Reverse transfer capacitance	_	5	_			
C _{O(er)}	Output capacitance, energy related b	_	54	_	, F	V _{GS} =0V, V _{DS} =0V to 600V	
$C_{O(tr)}$	Output capacitance, time related °	_	88	_	pF		
Q _G	Total gate charge	_	10	_			
Q _{GS}	Gate-source charge	_	2.6	_	nC	V _{DS} =600V, V _{GS} =8V, I _D =10A	
Q_{GD}	Gate-drain charge	_	2.9	_			
Qoss	Output charge	_	53	_	nC	V _{GS} =0V, V _{DS} =0V to 600V	
t _{D(on)}	Turn-on delay	_	26	_		V_{DS} =600V, V_{GS} =8V, I_{D} =10A, R_{G} =22 Ω	
t _R	Rise time	_	5	_	no		
$t_{\text{D(off)}}$	Turn-off delay	_	40	_	ns		
t _F	Fall time	_	7.4	_			

Dynamic on-resistance; see Figures 19 and 20 for test circuit and conditions Equivalent capacitance to give same stored energy as V_{DS} rises from OV to 600V b.

Equivalent capacitance to give same charging time as V_{DS} rises from OV to 600V

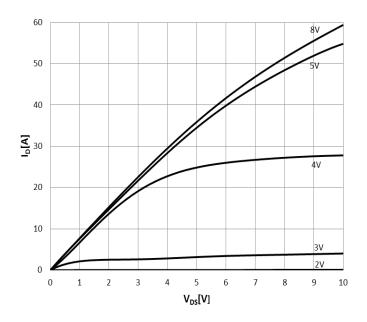
Electrical Parameters (T_J=25 °C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	
Reverse Dev	Reverse Device Characteristics						
Is	Reverse current	_	_	9.5	А	V _{GS} =0V, T _C =100°C, ≤25% duty cycle	
V_{SD}	B	_	2.3	_	V	V _{GS} =0V, I _S =10A	
VSD	Reverse voltage ^a	_	1.6	1.9	v	V _{GS} =0V, I _S =5A	
t _{RR}	Reverse recovery time	_	32	_	ns	I _s =10A, V _{DD} =600V,	
Q_{RR}	Reverse recovery charge	_	49	_	nC	di/dt=1000A/μs	
(di/dt) _{RDMC}	Reverse diode di/dt, repetitive b	_	_	1200	A/µs		
I _{RDMC1}	Reverse diode switching current, repetitive (dc) c, e	_	_	11	А	Circuit implementation and parameters on page 3	
I _{RDMC2}	Reverse diode switching current, repetitive (ac) c, e	_	_	14	А	Circuit implementation and parameters on page 3	
(di/dt) _{RDMT}	Reverse diode di/dt, transient d	_	_	2400	A/µs		
I _{RDMT}	Reverse diode switching current, transient d,e	_	_	18	А	A Circuit implementation and parameters on page 3	

Notes:

- Includes dynamic R_{DS(on)} effect
- Continuous switching operation
- Definitions: dc = dc-to-dc converter topologies; ac = inverter and PFC topologies, 50-60Hz line frequency ≤300 pulses per second for a total duration ≤20 minutes c.
- d.
- I_{RDM} values can be increased by increasing R_{G} and C_{SN} on page 3

Typical Characteristics (T_C =25 $^{\circ}$ C unless otherwise stated)



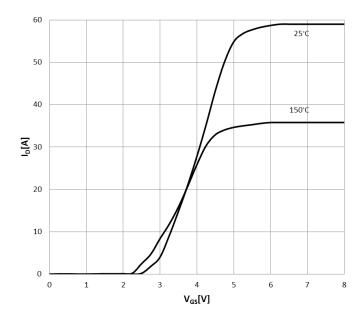
40 8V 35 30 4V 25 <u>8</u> 20 15 3V 10 0 3 4 5 7 9 0 10 $V_{DS}[V]$

Figure 1. Typical Output Characteristics T_J=25 °C

Parameter: V_{GS}

Figure 2. Typical Output Characteristics T_J=150 °C

Parameter: V_{GS}



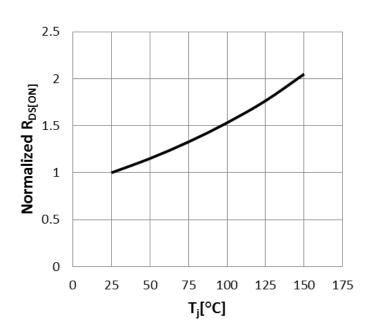
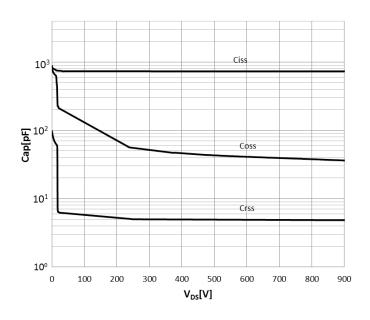


Figure 3. Typical Transfer Characteristics

Figure 4. Normalized On-resistance

 V_{DS} =10V, parameter: T_J I_D =10A, V_{GS} =8V

Typical Characteristics (T_C=25 °C unless otherwise stated)



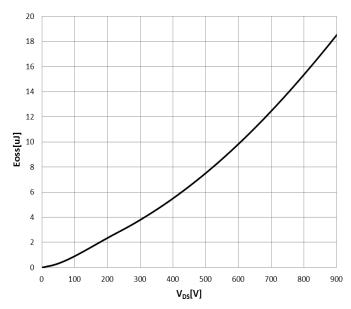
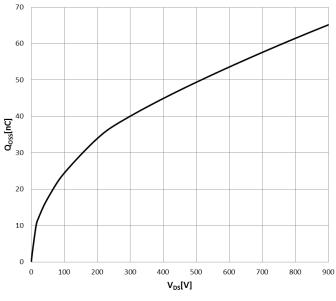
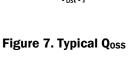


Figure 5. Typical Capacitance V_{GS} =0V, f=1MHz

Figure 6. Typical Coss Stored Energy





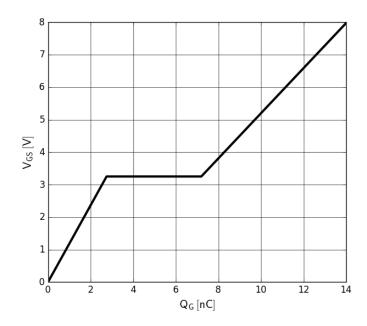
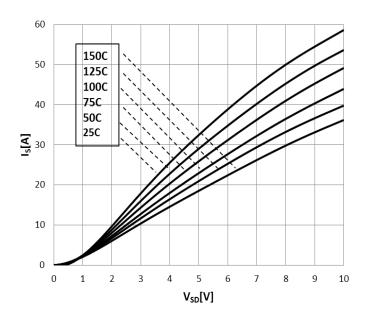


Figure 8. Typical Gate Charge IDS=10A, VDS=600V

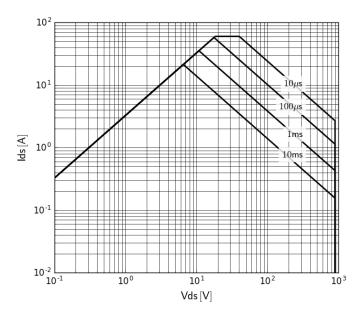
Typical Characteristics (T_C=25 °C unless otherwise stated)



35 30 D = 10%25 Peak I_D [A] D = 20%20 D = 50%DC 10 0 L 25 125 150 175 200 $T_{case} \, [^{\circ}C]$

Figure 9. Forward Characteristics of Rev. Diode $I_S {=} f(V_{SD}), \ parameter \ T_J$

Figure 10. Current Derating
Pulse width = 100µs



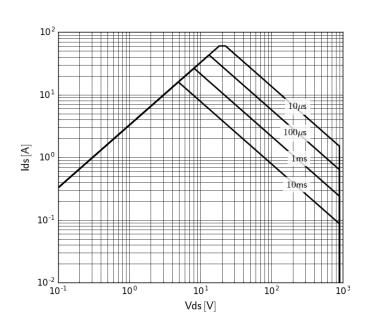
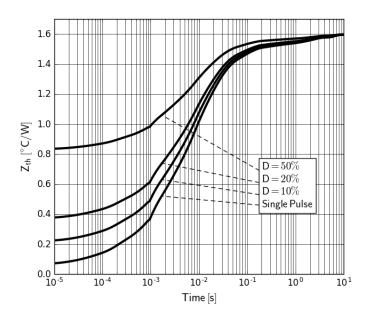


Figure 11. Safe Operating Area T_c=25°C (calculated based on thermal limit)

Figure 12. Safe Operating Area T_c=80 °C (calculated based on thermal limit)

Typical Characteristics (T_C=25 °C unless otherwise stated)



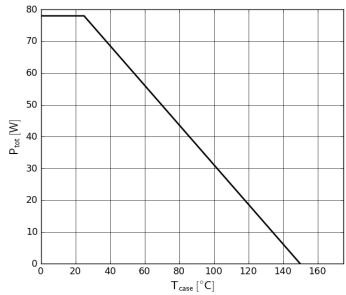


Figure 13. Transient Thermal Resistance

Figure 14. Power Dissipation

Test Circuits and Waveforms

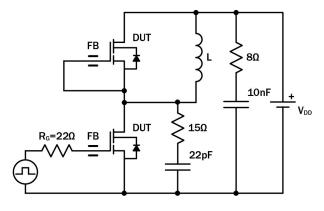


Figure 15. Switching Time Test Circuit (see circuit implementation on page 3 for methods to ensure clean switching)

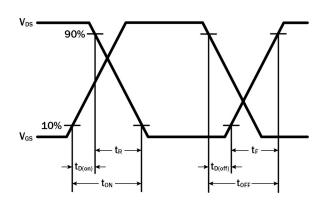


Figure 16. Switching Time Waveform

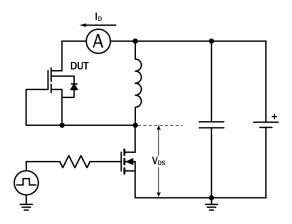


Figure 17. Diode Characteristics Test Circuit

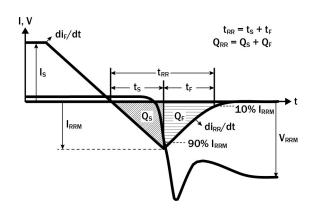


Figure 18. Diode Recovery Waveform

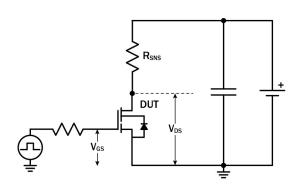


Figure 19. Dynamic R_{DS(on)eff} Test Circuit

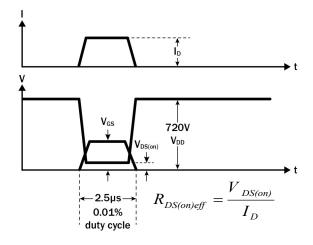


Figure 20. Dynamic RDS(on)eff Waveform

Design Considerations

The fast switching of GaN devices reduces current-voltage crossover losses and enables high frequency operation while simultaneously achieving high efficiency. However, taking full advantage of the fast switching characteristics of GaN switches requires adherence to specific PCB layout guidelines and probing techniques.

Before evaluating Transphorm GaN devices, see application note <u>Printed Circuit Board Layout and Probing for GaN Power Switches</u>. The table below provides some practical rules that should be followed during the evaluation.

When Evaluating Transphorm GaN Devices:

DO	DO NOT
Minimize circuit inductance by keeping traces short, both in the drive and power loop	Twist the pins of TO-220 or TO-247 to accommodate GDS board layout
Minimize lead length of TO-220 and TO-247 package when mounting to the PCB	Use long traces in drive circuit, long lead length of the devices
Use shortest sense loop for probing; attach the probe and its ground connection directly to the test points	Use differential mode probe or probe ground clip with long wire
See AN0003: Printed Circuit Board Layout and Probing	

GaN Design Resources

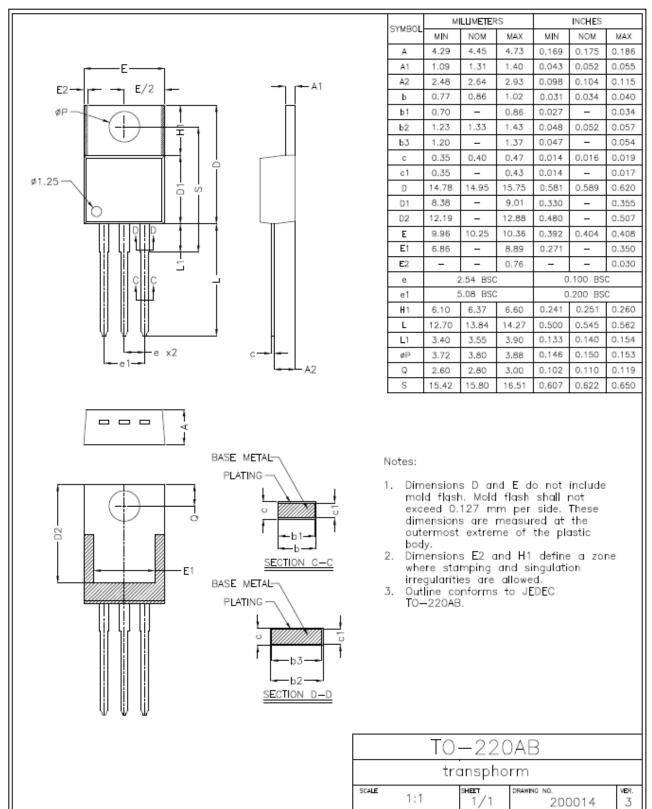
The complete technical library of GaN design tools can be found at transphormusa.com/design:

- Reference designs
- Evaluation kits
- Application notes
- · Design guides
- Simulation models
- Technical papers and presentations

Mechanical

3 Lead TO-220 (PS) Package

Pin 1: Gate; Pin 2: Source; Pin 3: Drain, Tab: Source



Revision History

Version	Date	Change(s)	
0	11/10/2017	Release final datasheet	
1	3/7/2021	Product discontinued	